Moonstone Hardware Test Report Results

R4028-M1015-01
Version: 1.0
May 7, 2024

Celestica

Parameter	Specification	Measured Results	Status
Frequency	<100Khz	98.8140E+3Hz	TESTRes
Clock High	$>4\mu$s	4.9476E-6s	TESTRes
Clock Low	$>4\mu$s	5.1725E-6s	TESTRes
$V_{Clockmax}$	<3.57V	3.4000V	TESTRes
$V_{Clockmin}$	>-.5V	40.0000E-3V	TESTRes
$V_{Clockih}$	2.31-3.6V	3.3600V	TESTRes
$V_{Clockil}$	-.5-.99V	120.0000E-3V	TESTRes
$V_{Datamax}$	<3.57V	3.4000V	TESTRes
$V_{Datamin}$	>-.5V	40.0000E-3V	TESTRes
V_{Dataih}	2.31-3.6V	3.3200V	TESTRes
V_{Datail}	-.5-.99V	80.0000E-3V	TESTRes
Clock Rise Time	<1000ns	201.6602E-9s	TESTRes
Clock Fall Time	<300ns	7.0431E-9s	TESTRes
Data Rise Time	<1000ns	208.6589E-9s	TESTRes
Data Fall Time	<300ns	7.1467E-9s	TESTRes
Data Setup Time	>250ns	4.9800E-6SECONDS	TESTRes
Data Hold time	> 0ns	540.0000E-9SECONDS	TESTRes
Start Condition Hold Time	$> 4\mu$s	540.0000E-9SECONDS	TESTRes
Stop Condition Setup Time	$> 4\mu$s	540.0000E-9SECONDS	TESTRes

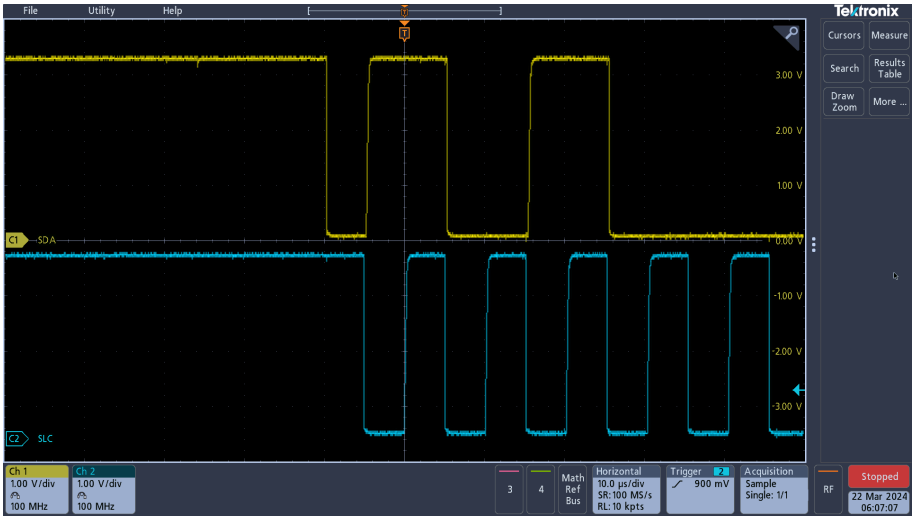

Figure 1: Waveform

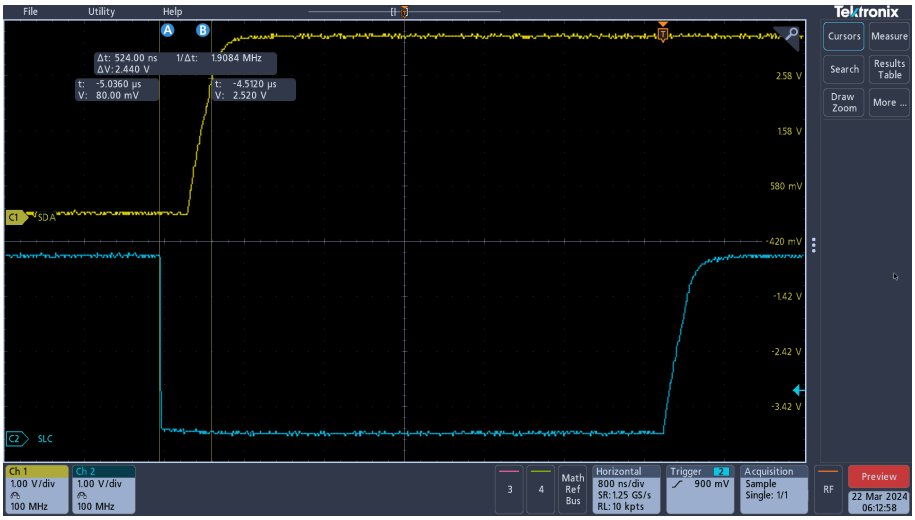

Figure 2: Data Hold Time

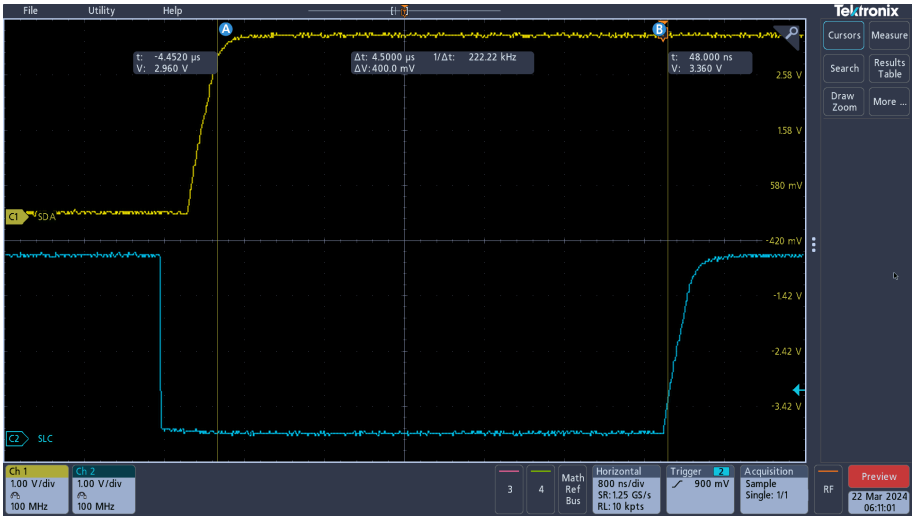

Figure 3: Data Setup Time

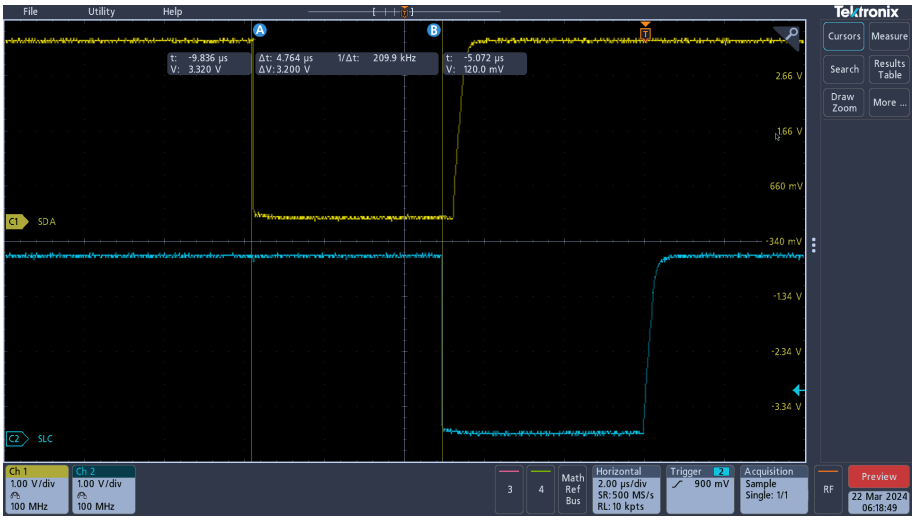

Figure 4: Start Condition

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Data Hold time	> 0ns	540.0000E-9SECONDS	TESTRes
Start Condition Hold Time	> 4μs	540.0000E-9SECONDS	TESTRes
Stop Condition Setup Time	> 4μs	540.0000E-9SECONDS	TESTRes

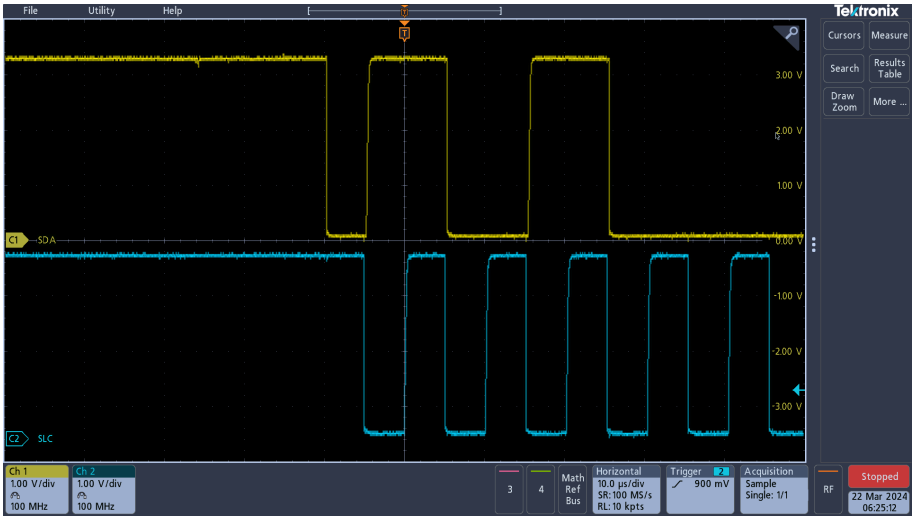

Figure 5: Waveform

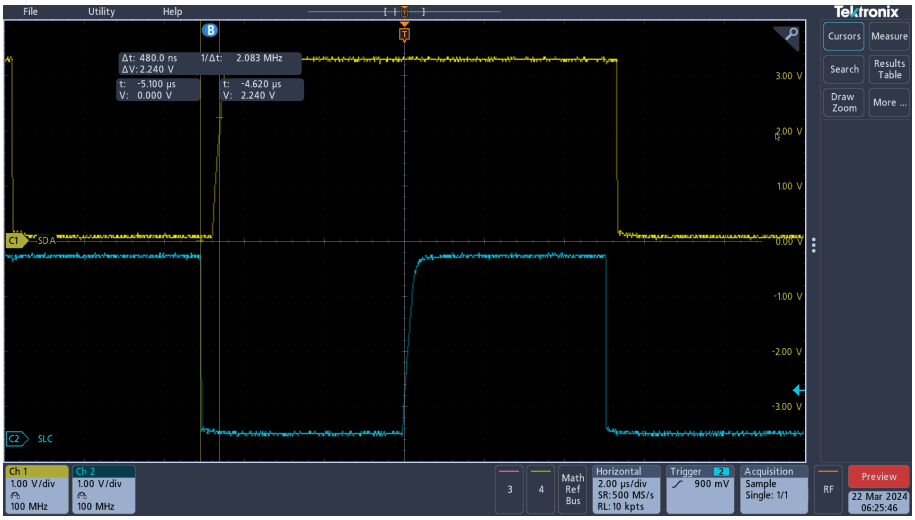

Figure 6: Data Hold Time

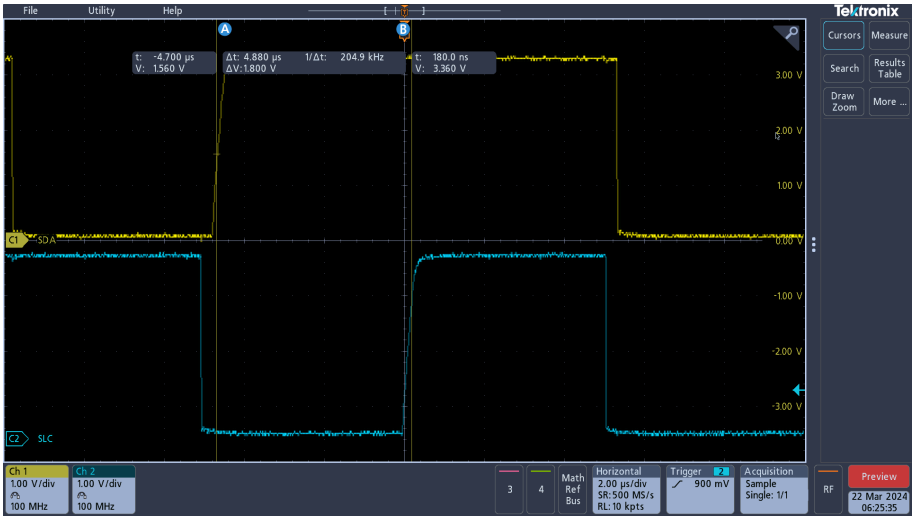

Figure 7: Data Setup Time

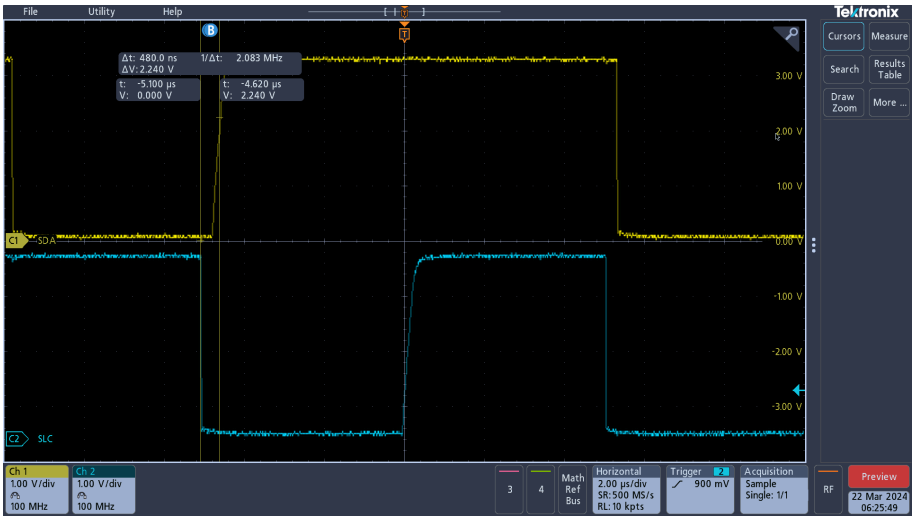

Figure 8: Start Condition

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Stop Condition Setup Time	> 4μs	540.0000E-9SECONDS	TESTRes

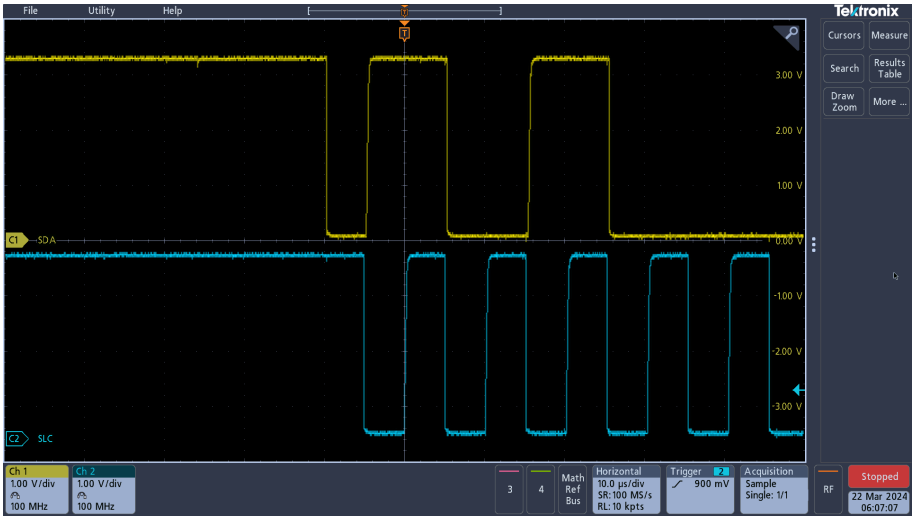

Figure 9: Waveform

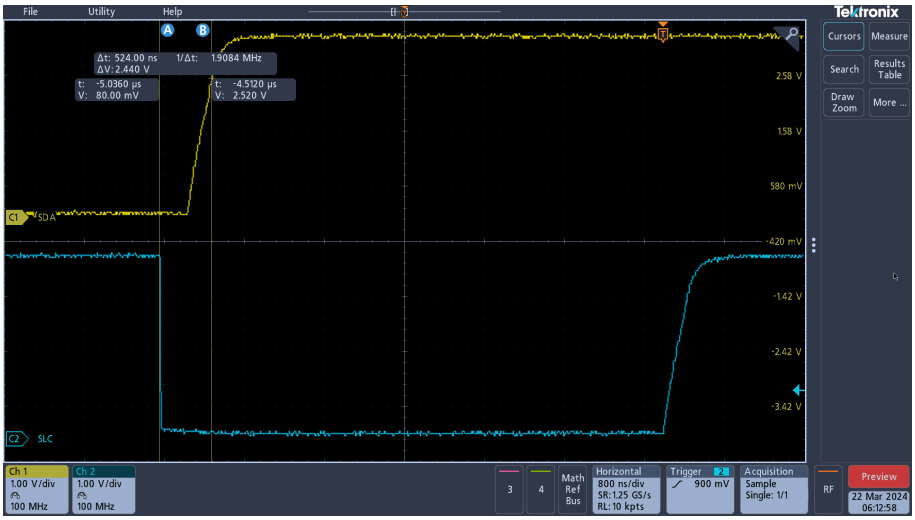

Figure 10: Data Hold Time

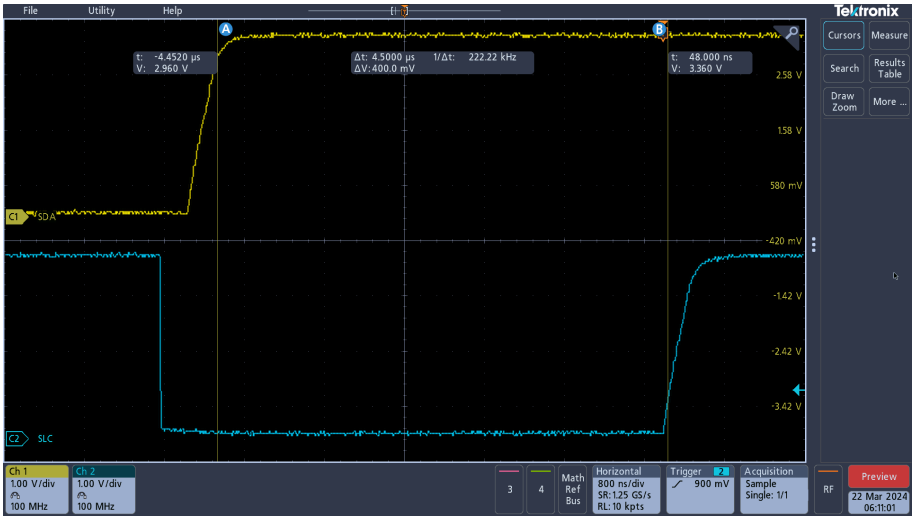

Figure 11: Data Setup Time

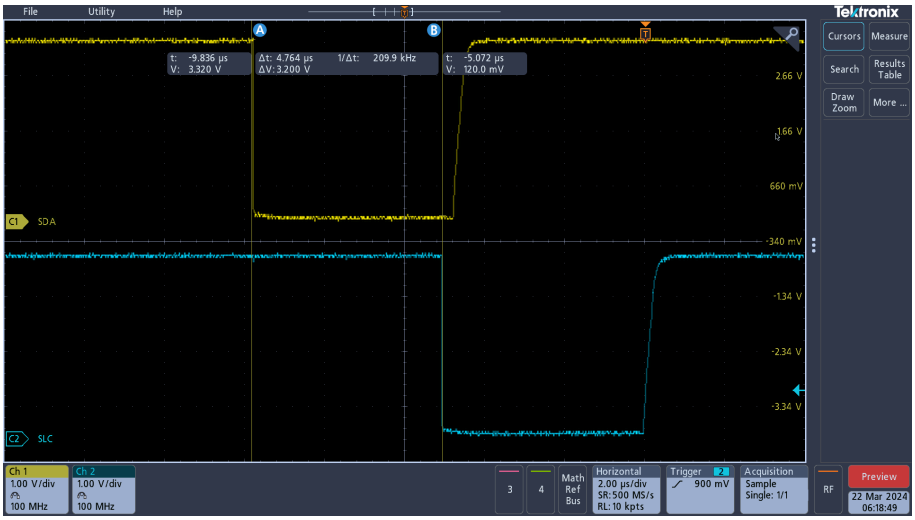

Figure 12: Start Condition